

14. (Amended) A method of forming a transistor, comprising:
- forming first and second source/drain regions;
  - forming a body region between the first and second source/drain regions;
  - evaporation depositing a metal layer on the body region using [a substantially thermal process] electron beam evaporation, the metal being chosen from the group IVB elements of the periodic table;
  - oxidizing the metal layer to form a metal oxide layer on the body region; and
  - coupling a gate to the metal oxide layer.
22. (Amended) A method of forming a memory array, comprising:
- forming a number of access transistors, comprising:
    - forming first and second source/drain regions;
    - forming a body region between the first and second source/drain regions;
    - evaporation depositing a metal layer on the body region using [a substantially thermal process] electron beam evaporation, the metal being chosen from the group IVB elements of the periodic table;
    - oxidizing the metal layer to form a metal oxide layer on the body region;
    - coupling a gate to the metal oxide layer;
  - forming a number of wordlines coupled to a number of the gates of the number of access transistors;
  - forming a number of sourcelines coupled to a number of the first source/drain regions of the number of access transistors; and
  - forming a number of bitlines coupled to a number of the second source/drain regions of the number of access transistors.
30. (Amended) A method of forming an information handling system, comprising:
- forming a processor;
  - forming a memory array, comprising:
    - forming a number of access transistors, comprising:

forming first and second source/drain regions;  
forming a body region between the first and second source/drain regions;  
evaporation depositing a metal layer on the body region using [a substantially thermal process] electron beam evaporation, the metal being chosen from the group IVB elements of the periodic table;  
oxidizing the metal layer to form a metal oxide layer on the body region;  
coupling a gate to the metal oxide layer;  
forming a number of wordlines coupled to a number of the gates of the number of access transistors;  
forming a number of sourcelines coupled to a number of the first source/drain regions of the number of access transistors;  
forming a number of bitlines coupled to a number of the second source/drain regions of the number of access transistors; and  
forming a system bus that couples the processor to the memory array.

51. (Amended) A transistor formed by the process, comprising:

forming a body region coupled between a first source/drain region and a second source/drain region;

evaporation depositing a metal layer on the body region using [a substantially thermal process] electron beam evaporation, the metal being chosen from the group IVB elements of the periodic table;

oxidizing the metal layer to form a metal oxide layer on the body region; and  
coupling a gate to the metal oxide layer.

55. (Amended) A method of forming a gate oxide on a transistor body region, comprising:

electron beam evaporation depositing a [metal] zirconium layer on the body region[, the metal being chosen from the group IVB elements of the periodic table]; and

oxidizing the [metal] zirconium layer to form a metal oxide layer on the body region.